

**Search Notes**

Application/Control No.

10/701,156

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under  
Reexamination

IWATA, YUJI

Art Unit

2861

**SEARCHED**

Class	Subclass	Date	Examiner
347	updated	5/16/2006	SWH
392	updated	5/16/2006	SWH
34	updated	5/16/2006	SWH
219	updated	5/16/2006	SWH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR